

<b>Notice of References Cited</b>	Application/Control No. 09/866,936	Applicant(s)/Patent Under Reexamination YANG ET AL.	
	Examiner Timothy M. Harbeck	Art Unit 3628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mary Lindahl, "Risk-Return Hedging Effectiveness Measures for Stock Index Futures; INTRODUCTION," The Journal of Futures Markets, New York: Aug 1991. Vol.11, Iss. 4; pg 399, 11 pgs.
	V	A.G. Malliaris and Jorge Urrutia, "Tests of Random Walk of Hedge Ratios and Measures of Hedging Effectiveness for Stock Indexes and Foreign Currencies," The Journal of Futures Markets, Hoboken: Feb 1991. Vol.11, Iss. 1; pg 55, 14 pgs.
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	X	

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